

Transmission electron microscopy and electron energy loss spectroscopy (2:0, Jan-Apr)

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Syllabus:

1. Basics of TEM: instrument, electron source, aperture, recording system, spectrometer etc.
2. Image formation in a TEM: resolution, various contrast in TEM such as diffraction contrast, phase contrast, Z-contrast, magnetic contrast, energy filtered TEM etc
3. Concept of phase contrast microscopy in a TEM, aberration corrected TEM, imaging with negative C_s , imaging of light elements and quantification.
4. STEM-HAADF imaging in TEM, aberration corrected STEM and atom by atom imaging.
5. Principle of Gun monochromator, high resolution electron energy loss spectroscopy, application of HREELS e.g., band gap measurement, plasmon mode determination, probing electronic structure by ELNES, bonding environment and atom by atom imaging and spectroscopy
6. Newer developments in ultra high resolution TEM
7. Some demonstrations of technique

References:

- A. Transmission electron microscopy by David B. Williams and C. Barry Carter
- B. High resolution electron microscopy by J.C.H. Spence
- C. Transmission electron microscopy and diffractometry by Brent Fultz and James M. Howe